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EDGE ARTICLE

Kinetics-driven high power Li-ion battery with *a*-Si/NiSi_x core-shell nanowire anodes†

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We report amorphous-Si nanowire shell anodes, supported by NiSi_x nanowire cores, by catalyst-free two-step SiH₄ chemical vapor deposition, where the metallic core acts as a mechanical supporter and a kinetically unlimited charge supplier. We have achieved highly reversible capacitance of over 3000 mAh g⁻¹ even at a 2C rate, with stable cyclic retention which stems from the altered electrochemical reactions with relatively small volume expansion routes by a kinetic effect.

Introduction

Anode architectures, particularly when they are three-dimensional at the nanometre scale, are closely related with cell performances in Li-ion batteries.^{1–6} Therein, the achievable electrochemical capacity and the power characteristics are inherently determined by a series of phase transitions involved in the anode during lithiation/delithiation. The electrochemical Li–Si system forms various Li-rich Li_xSi intermetallics (0 ≤ *x* ≤ 4.4), correspondingly symptomatic of the largest known gravimetric charge capacity of up to 4200 mAh g⁻¹ in the bulk limit, thus can represent an attractive anodic system for the high capacity Li-ion battery.^{1,3–5}

However, the system undergoes notoriously large volume-changes up to 400% during the cyclic lithiation and delithiation, resulting in poor cyclic retention in its cell capacity and output power.^{1,3–5} It is suggested that this severe anode pulverization upon the cyclic volume changes can be alleviated by adopting one-dimensional Si nanocrystals, such as Si nanowires (NWs), based on the promises of their affordable accommodation of large volume-changes and the efficient charge collection capability.^{4,5,7–11} Yet, monolithic single-crystalline Si NWs exhibit cyclic degradation in their cell capacity particularly at the high

charging/discharging rate, thus limiting their integration into the high power cells.^{5,12–18}

Here, we report amorphous-Si (*a*-Si) shell anodes, supported by NiSi_x NW cores, by a catalyst-free two-step SiH₄ chemical vapor deposition, where the metallic core acts as a mechanical supporter and a kinetically unlimited charge supplier. Spontaneous silicide NWs, such as NiSi_x, FeSi, CoSi, TaSi₂^{19–27} NWs, have been recently investigated, and among others NiSi_x NWs are of particular interest because their growth can be easily integrated with silicon processing technology. Besides, NiSi_x exhibits the lowest resistivity and makes good contacts with Si.^{25–27} In this regard, we designed the core-shell NW anode architecture in this work. We have achieved the highly reversible capacity over 3000 mAh g⁻¹ even at 2C rate, with stable cyclic retention which stems from the altered electrochemical reactions with relatively small volume expansion routes by a kinetic effect.

Results and discussion

a-Si NW shells, supported by metallic NiSi_x NW cores (*a*-Si/NiSi_x NW), were grown by a simple two-step SiH₄ CVD process: (i) the self-catalytic NiSi_x NWs were grown on Ni thin films, (ii) followed by *a*-Si shells deposition on the NiSi_x NWs, as illustrated in Fig. 1(a). We start off the NiSi_x NW synthesis by thermal evaporation of Ni films on Ag-coated stainless steel (SUS) substrates of a circular shape disk in 15mm diameter. Ag acts as a diffusion barrier of Fe from SUS into the Ni films. The Ni/Ag/SUS substrates were annealed with oxygen at 400 °C, and then reacted with 50 Torr of SiH₄ (10% diluted in H₂) at 420 °C, as described in Ref. 26,27. The *a*-Si shell deposition was conducted by using thermal decomposition of SiH₄ (10% diluted in H₂) at 550 °C for 30 min. Here we note that *a*-Si shells are formed, when NiSi_x NWs are oxygen-exposed prior to the SiH₄ flows, whereas the crystalline Si shell (*c*-Si) was formed otherwise, as shown in Fig. S1.† We also prepared *a*-Si shell NWs on the insulating *c*-Si core NWs, and describe a series of

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† Electronic supplementary information (ESI) available: Structure of *c*-Si/NiSi_x NW, a photograph of the *a*-Si/NiSi_x NW grown on substrate, normalization method for calculating the gravimetric capacity, and current charge/discharge curve for NiSi_x NW cell in the galvanostatic mode. See DOI: 10.1039/c0sc00628a

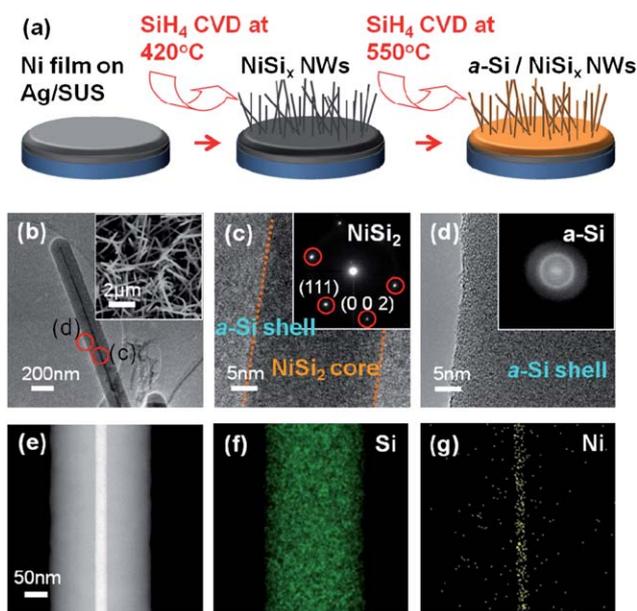


Fig. 1 (In color) (a) The schematics of the NW heterostructure growth in this study. (b) TEM image of an individual *a*-Si/NiSi_x NW. The inset shows a plan-view SEM image of *a*-Si/NiSi_x NWs grown on SUS substrate. (c) HRTEM image of an individual *a*-Si/NiSi_x NW at the core region and the corresponding FFT-DP along the [1–10] zone axis (inset). (d) HRTEM image of an individual *a*-Si/NiSi_x NW at the shell region and the corresponding FFT-DP (inset). (e) HAADF image of *a*-Si/NiSi_x NW. (f and g) EDX elemental mapping images of Si (f) and Ni (g) in (e).

comparative cyclic cell performances in greater details,²⁸ and discuss them around the roles of the metallic core for altered electrochemical reactions.^{29,30}

Fig. 1(b) shows the representative microstructures of *a*-Si/NiSi_x NWs by transmission electron microscope (TEM), where the average diameter of *a*-Si/NiSi_x NW is 190 nm with the 20 nm thick NiSi_x core NWs. Scanning electron microscope (SEM) images in the inset illustrate that the shell NWs were conformally deposited onto the whole NWs in the substrate – see also Fig. S2 in Supporting Information.† High-resolution TEM (HRTEM) images and corresponding fast fourier transform diffraction patterns (FFT-DP) in Fig. 1(c) and 1(d) confirm that Si/NiSi_x NW features amorphous Si NW shells and single-crystalline NiSi₂ NW cores.³¹ High-angle annular dark field (HAADF) images, where the intensity is roughly proportional to square of atomic number, and energy dispersive X-ray spectroscopy (EDX) mapping images in Fig. 1(e), (f) and (g) also demonstrate that core/shell NW structures are clearly discernable, and the elemental distribution of Ni is locally limited in the core region within the instrumental resolution.

The *a*-Si/NiSi_x NW anodes were incorporated into a coin-type half cell (CR2016 coin-type). The cell uses Li metal foils as the counter and the reference electrode, and 1M LiPF₆ dissolved in a 1 : 1 (by volume, provided by Techono. Semichem. Co.) mixture of ethylene carbonate (EC) and diethyl carbonate (DEC) as the electrolyte. The cell assembly was carried out in an Ar-filled glove box with less than 0.1 ppm each of oxygen and moisture. The charge capacity of the *a*-Si/NiSi_x NW cell was measured over the potential range of 0.01 to 2.00 V (vs. Li/Li⁺)

during the initial 50 cycles in the galvanostatic mode. The measured discharge capacity is carefully normalized into the gravimetric capacity, as described in Fig. S3.†

Fig. 2 shows the cyclic retention of two types of NWs: *a*-Si/NiSi_x NW cells and *a*-Si/*c*-Si NW cells. It is found that *a*-Si/NiSi_x NWs retain almost the 83% of the first discharge capacity after the 50th cycle with the high charge capacity above 3000 mAh g⁻¹. For a check, we tested the bare NiSi_x NW anodes in the galvanostatic mode; however, we did not observe any apparent potential plateau over the potential range of 0.01 to 3.00 V – also see Fig. S4.† This suggests that the bare NiSi_x NWs alone are electrochemically inactive in our experimental conditions. We have also tested the rate dependent capacity by charging the cell at a constant rate of 0.1C and discharging it at the various rate from 0.1C to 2C (1C ≡ 1 h per half-cycle). Fig. 2(b) shows that the discharge capacity of *a*-Si/NiSi_x NWs is maintained over 94% of the first discharge capacity, and weakly depends on the C-rate up to 2C. The discharge capacity of *a*-Si/*c*-Si NWs, on the other hand, fades significantly and strongly depends on the C-rate. It is obvious that a combination of *a*-Si shells and metallic NiSi_x NW cores is responsible for the unprecedented reversible lithiation/delithiation in *a*-Si shells at the high charge/discharge rate.

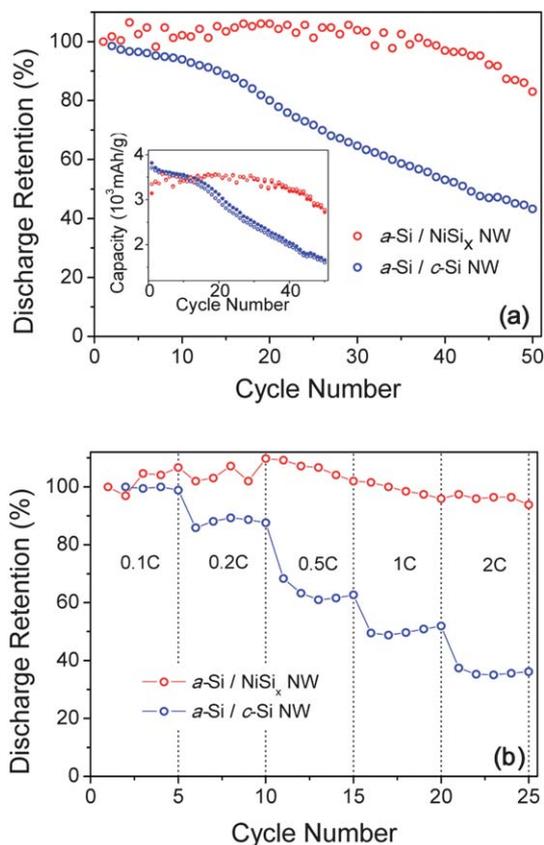


Fig. 2 (In color) (a) The discharge capacity retention for the *a*-Si/NiSi_x NW (red circles) and the *a*-Si/*c*-Si NW (blue circles), respectively. The inset shows the specific capacity for the *a*-Si/NiSi_x NW (red close circles-charge and red open circles-discharge) and the *a*-Si/*c*-Si NW (blue close circles-charge and blue open circles-discharge), respectively. (b) The rate capability for the *a*-Si/NiSi_x NW (red circles) and the *a*-Si/*c*-Si NW (blue circles), respectively.

Fig. 3(a–c) present HRTEM and HAADF images of *a*-Si/*c*-Si NWs after the 50 cycles, where they become porous and pulverized upon the cyclic lithiation/delithiation. By striking contrast, *a*-Si/NiSi_x NWs maintain the initial core/shell NW structures. Apparently, the structural robustness in *a*-Si/NiSi_x NWs, guaranteed from a mechanical supporter of NiSi_x cores, is responsible for the enhanced cyclic retention and rate capability, as shown in Fig. 3(d–f).

In order to further investigate the electrochemical roles of the metallic NiSi_x cores, we tried to compare the differential capacity plots for *a*-Si/NiSi_x NWs with those of *a*-Si/*c*-Si NWs, as in Fig. 3 (g). After the 1st cycle, which is called the formation or activation process, *a*-Si/*c*-Si NWs and *a*-Si/NiSi_x NWs display two reduction peaks around 260 mV and 80 mV, as marked by *A* and *B*, and they are associated with the formations of intermetallic compounds, Li_xSi. Reportedly, the 260 mV and 80 mV peaks are assigned to the formation of amorphous Li_xSi (*a*-Li_xSi) from *a*-Si and *c*-Si, respectively.^{32–34} Although other small reduction peaks below 80 mV, marked as *C* and *C'*, are not well identified, they are usually assigned to either routes for *a*-Li_xSi to *a*-Li_{x+y}Si (fully lithiated amorphous lithium silicides) transition or *a*-Li_xSi to *c*-Li₂Si (fully lithiated crystalline lithium silicides) transition.

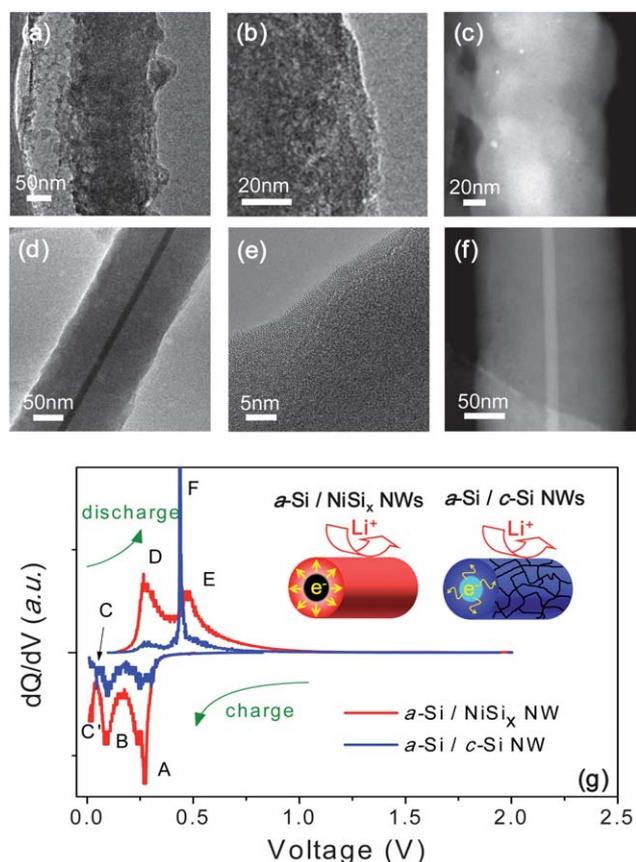


Fig. 3 (In color) (a–f) TEM images of individual *a*-Si/*c*-Si NW and *a*-Si/NiSi_x NW after 50th cycling. (a) Low magnification TEM image of *a*-Si/*c*-Si NW. (b) HRTEM image of *a*-Si/*c*-Si NW at the surface. (c) HAADF image of *a*-Si/*c*-Si NW. (d) Low magnification TEM image of *a*-Si/NiSi_x NW. (e) HRTEM image of *a*-Si/NiSi_x NW at the surface. (f) HAADF image of *a*-Si/NiSi_x NW. (g) The differential capacity of the 10th cycle for the *a*-Si/NiSi_x NW (red line), the *a*-Si/*c*-Si NW (blue line).

Identification of the fully lithiated phase whether it is *a*-Li_xSi to *c*-Li₂Si is critical, since the *a*-Li_xSi to *c*-Li₂Si or *vice versa* among the series of lithiation/delithiation reactions involves the largest volume changes, which is in turn the major source for the deterioration in the anodic reversibility.^{34–37} During the discharge process, *a*-Si/*c*-Si NWs display the dominant oxidation peak at 450 mV, marked as *F*, assigned to the dissociation of *c*-Li₂Si to *a*-Li_xSi or *a*-Si, indicating that its reduction peak below 80 mV corresponds to the nucleation of a crystalline lithium silicide (*c*-Li₂Si).^{34–36} By contrast, *a*-Si/NiSi_x NWs exhibit two dissimilar oxidation peaks between 250 mV and 500 mV, marked as *D* and *E*, which are assigned to the dissociation of *a*-Li_{x+y}Si to *a*-Li_xSi or *a*-Si.^{32,34,37} This finding can be back-traced to assign another phase transition, *C'* during the Li charging to the formation of *a*-Li_{x+y}Si. In other words, the full lithiation into *a*-Li_{x+y}Si in *a*-Si/NiSi_x, instead of *c*-Li₂Si in *a*-Si/*c*-Si NWs, alleviates severe physical pulverization and leads to the stable reversibility in the cyclic cell performance. We speculate that kinetically unlimited electron supply from NiSi_x NW core coupled with the properly absorbed volume change by *a*-Si shell provides alternative electrochemical reactions of *a*-Si/NiSi_x NWs to skip over the nucleation of *c*-Li₂Si by a kinetic effect. We measured average resistivity of NiSi_x NWs and *c*-Si NWs to be 10⁻³ Ω·cm, and 10³ Ω·cm. It is known that monolithic Si crystals usually undertake temporal local-concentration of Li ions in Si matrices, followed by the rapid and spatially inhomogeneous evolution of fully lithiated crystalline lithium silicides (*c*-Li₂Si), which in turn results in severe Si pulverizations. Instead, we argue that uniform distribution of the electrochemical potential in our *a*-Si/NiSi_x NWs, which is provided by the metallic NiSi_x cores is responsible for the reversible reaction route mediated by fully lithiated amorphous lithium silicides.^{3,32,36}

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